

Notice of References Cited	Application/Control No. 10/542,017	Applicant(s)/Patent Under Reexamination TAKEDA ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,430,566	07-1995	Sakaya et al.	349/118
*	C	US-6,088,079	07-2000	Kameyama et al.	349/185
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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